

**MOTOROLA
SEMICONDUCTOR**
TECHNICAL DATA

Power Field Effect Transistors
N-Channel Enhancement-Mode
Silicon Gate TMOS

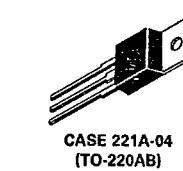
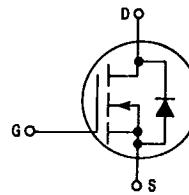
These TMOS Power FETs are designed for low voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

- Silicon Gate for Fast Switching Speeds
- Low $r_{DS(on)}$ to Minimize On-Losses
- Rugged — SOA is Power Dissipation Limited
- Source-to-Drain Diode Characterized for Use With Inductive Loads



**IRFZ30
IRFZ32**

TMOS POWER FETs
25 and 30 AMPERES
 $r_{DS(on)} = 0.05 \text{ OHM}$
50 VOLTS
 $r_{DS(on)} = 0.07 \text{ OHM}$



CASE 221A-04
(TO-220AB)

MAXIMUM RATINGS

Rating	Symbol	Device		Unit
		IRFZ30	IRFZ32	
Drain-Source Voltage	V_{DSS}	50		Vdc
Drain-Gate Voltage ($R_{GS} = 1 \text{ M}\Omega$)	V_{DGR}	50		Vdc
Gate-Source Voltage	V_{GS}	± 20		Vdc
Drain Current — Continuous @ $T_C = 25^\circ\text{C}$ — Continuous @ $T_C = 100^\circ\text{C}$ — Pulsed @ $T_C = 25^\circ\text{C}$	I_D I_{DM}	30 19 80	25 16 60	Adc
Total Power Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	75 0.6		Watts W/ $^\circ\text{C}$
Operating and Storage Temperature Range	T_J, T_{stg}	-65 to 150		°C

THERMAL CHARACTERISTICS

Thermal Resistance — Junction to Case — Junction to Ambient	$R_{\theta JC}$	1.67 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 5 Seconds	T_L	300	°C

See the MTP30N05E Designer's Data Sheet for a complete set of design curves for the product on this data sheet.

MOTOROLA TMOS POWER MOSFET DATA

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Drain-Source Breakdown Voltage ($V_{GS} = 0$, $I_D = 0.25 \text{ mA}$)	$V_{(BR)DSS}$	50	—	Vdc
Zero Gate Voltage Drain Current ($V_{DS} = \text{Rated } V_{DSS}$, $V_{GS} = 0$) ($V_{DS} = 0.8 \text{ Rated } V_{DSS}$, $V_{GS} = 0$, $T_J = 125^\circ\text{C}$)	I_{DSS}	— —	0.2 1	mAdc
Gate-Body Leakage Current, Forward ($V_{GSF} = 20 \text{ Vdc}$, $V_{DS} = 0$)	I_{GSSF}	—	100	nAdc
Gate-Body Leakage Current, Reverse ($V_{GSR} = 20 \text{ Vdc}$, $V_{DS} = 0$)	I_{GSSR}	—	100	nAdc

ON CHARACTERISTICS*

Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 0.25 \text{ mA}$)	$V_{GS(\text{th})}$	2	4	Vdc	
Static Drain-Source On-Resistance ($V_{GS} = 10 \text{ Vdc}$, $I_D = 16 \text{ Adc}$)	IRFZ30 IRFZ32	$r_{DS(\text{on})}$	— —	0.05 0.07	Ohm
On-State Drain Current ($V_{GS} = 10 \text{ V}$) ($V_{DS} \geq 1.5 \text{ Vdc}$) ($V_{DS} \geq 1.75 \text{ Vdc}$)	IRFZ30 IRFZ32	$I_{D(\text{on})}$	30 25	— —	Adc
Forward Transconductance ($V_{DS} \geq 1.5 \text{ V}$, $I_D = 16 \text{ A}$) ($V_{DS} \geq 1.75 \text{ V}$, $I_D = 16 \text{ A}$)	IRFZ30 IRFZ32	g_{FS}	9 9	— —	mhos

DYNAMIC CHARACTERISTICS

Input Capacitance	($V_{DS} = 25 \text{ V}$, $V_{GS} = 0$, $f = 1 \text{ MHz}$)	C_{iss}	—	1600	pF
Output Capacitance		C_{oss}	—	800	
Reverse Transfer Capacitance		C_{rss}	—	200	

SWITCHING CHARACTERISTICS*

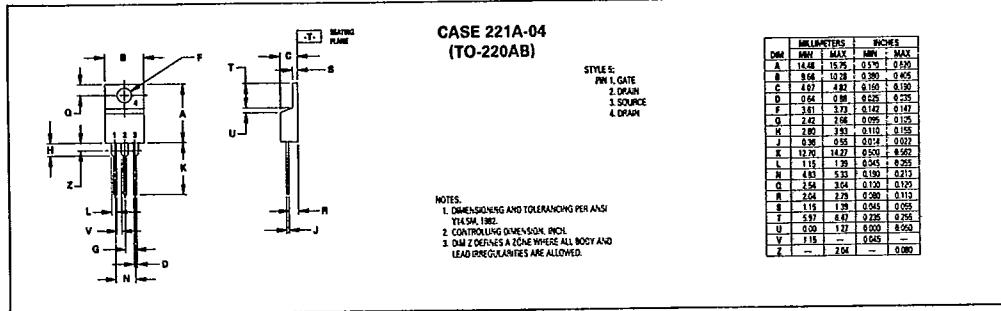
Turn-On Delay Time	($V_{DD} = 25 \text{ V}$, $I_D = 16 \text{ Apk}$, $R_{gen} = 50 \text{ Ohms}$)	$t_{d(on)}$	—	25	ns
Rise Time		t_r	—	35	
Turn-Off Delay Time		$t_{d(off)}$	—	45	
Fall Time		t_f	—	35	
Total Gate Charge	($V_{DS} = 0.8 \text{ Rated } V_{DSS}$, $V_{GS} = 10 \text{ Vdc}$, $I_D = \text{Rated } I_D$)	Q_g	26 (Typ)	30	nC
Gate-Source Charge		Q_{gs}	14 (Typ)	—	
Gate-Drain Charge		Q_{gd}	12 (Typ)	—	

SOURCE-DRAIN DIODE CHARACTERISTICS*

Forward On-Voltage	($I_S = \text{Rated } I_D$, $V_{GS} = 0$)	V_{SD}	1.2 (Typ)	1.5(1)	Vdc
Forward Turn-On Time		t_{on}	Limited by stray inductance		
Reverse Recovery Time		t_{rr}	150 (Typ)	—	ns

*Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2\%$.

(1) Add 0.1 V for IRFZ30.



MOTOROLA TMOS POWER MOSFET DATA

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Drain-Source Breakdown Voltage ($V_{GS} = 0$, $I_D = 0.25 \text{ mA}$)	$V_{(BR)DSS}$	50	—	Vdc
Zero Gate Voltage Drain Current ($V_{DS} = \text{Rated } V_{DSS}$, $V_{GS} = 0$) ($V_{DS} = 0.8 \text{ Rated } V_{DSS}$, $V_{GS} = 0$, $T_J = 125^\circ\text{C}$)	I_{DSS}	—	0.2 1	mA
Gate-Body Leakage Current, Forward ($V_{GSF} = 20 \text{ Vdc}$, $V_{DS} = 0$)	I_{GSSF}	—	100	nA
Gate-Body Leakage Current, Reverse ($V_{GSR} = 20 \text{ Vdc}$, $V_{DS} = 0$)	I_{GSSR}	—	100	nA
ON CHARACTERISTICS*				
Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 0.25 \text{ mA}$)	$V_{GS(\text{th})}$	2	4	Vdc
Static Drain-Source On-Resistance ($V_{GS} = 10 \text{ Vdc}$, $I_D = 9 \text{ Adc}$)	IRFZ20 IRFZ22	$r_{DS(on)}$	— 0.1 0.12	Ohm
On-State Drain Current ($V_{GS} = 10 \text{ V}$) ($V_{DS} \geq 1.5 \text{ Vdc}$) ($V_{DS} \geq 1.7 \text{ Vdc}$)	IRFZ20 IRFZ22	$I_D(\text{on})$	15 14	— Adc
Forward Transconductance ($V_{DS} \geq 1.5 \text{ V}$, $I_D = 9 \text{ A}$) ($V_{DS} \geq 1.7 \text{ V}$, $I_D = 9 \text{ A}$)	IRFZ20 IRFZ22	g_{FS}	5 5	— mhos
DYNAMIC CHARACTERISTICS				
Input Capacitance	$(V_{DS} = 25 \text{ V}, V_{GS} = 0$, $f = 1 \text{ MHz}$)	C_{iss}	—	850
Output Capacitance		C_{oss}	—	350
Reverse Transfer Capacitance		C_{rss}	—	100
SWITCHING CHARACTERISTICS*				
Turn-On Delay Time	$(V_{DD} \approx 25 \text{ V}, I_D = 9 \text{ Apk}$, $R_{gen} = 60 \text{ Ohms}$)	$t_{d(on)}$	—	30
Rise Time		t_r	—	90
Turn-Off Delay Time		$t_{d(off)}$	—	40
Fall Time		t_f	—	30
Total Gate Charge	$(V_{DS} = 0.8 \text{ Rated } V_{DSS}$, $V_{GS} = 10 \text{ Vdc}$, $I_D = \text{Rated } I_D$)	Q_g	12 (Typ)	17
Gate-Source Charge		Q_{gs}	9 (Typ)	—
Gate-Drain Charge		Q_{gd}	3 (Typ)	—
SOURCE-DRAIN DIODE CHARACTERISTICS*				
Forward On-Voltage	$(I_S = \text{Rated } I_D$, $V_{GS} = 0$)	V_{SD}	0.8 (Typ)	1.1(1)
Forward Turn-On Time		t_{on}	Limited by stray inductance	
Reverse Recovery Time		t_{rr}	100 (Typ)	—

*Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2\%$.
(1) Add 0.15 V for IRFZ20.

